

Remarks:

No new matter is added by the corrections which rectify typographical errors:

The first error on page 1 was clearly a mistype.


The measurements on page 6 were clearly meant to refer to μm which are the orders of magnitude common for semiconductor devices currently being manufactured. Also, this is clear from Figure 8 which refers to $w=25\mu\text{m}$, $w=50\mu\text{m}$, and $w=100\mu\text{m}$.

The word on page 6, line 31 was clearly meant to read "capacitance" since the word "compacitance" does not exist, and the units of fF, furthermore, make it clear that the parameter being referred to is capacitance.

A clean copy of the ~~application~~^{specification} is attached. Please note that the line numbers have changed in the new clean copy and that the new clean copy will be used in future when referring to page and line numbers.

Respectfully Submitted,

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Jurgen K. Vollrath

Vollrath & Associates
588 Sutter Street #531
San Francisco, CA 94102
Telephone: (408) 667 1289